

<b>Search Notes</b>  <b>*1082340</b>  <b>0*</b>	<b>Application/Control No.</b>  10823400	<b>Applicant(s)/Patent Under Reexamination</b>  BAUER ET AL.
	<b>Examiner</b>  Tae H Yoon	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
524	437	2/16/2008	/TY/
ATD		10/24/09	/TY/
ATD		2/12/10	/TY/
ATD		8/3/10	/TY/
ATD		2/18/11	/TY/

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	2/16 and 2/18/2008	/TY/
EAST	9/13/08	/TY/
EAST	2/12/09	/TY/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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